Modeling and Simulation Methods: Recent Advances and Applications

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Message from the Guest Editors

Modeling and simulation methods and applications provide powerful tools for designing, evaluating, and/or predicting new or existing complex systems and processes. The purpose of this Special Issue is to present recent advances in methods and applications that focus on any aspect of system or process modeling and simulation. We are seeking the latest original contributions that have not been published and are not currently under process in any other journal or conference. The potential topics of interest include but are not limited to: conceptual and theoretical models; discrete-event simulation; agent-based modeling; system dynamics; hybrid and multi-paradigm simulation; mathematical models; simulation optimization; neural and fuzzy modeling; and simulation languages, tools, methods, and applications.

Keywords

- modeling
- simulation
- agent-based modeling
- system dynamics
- discrete event simulation
- hybrid simulation
- mathematical modeling
- optimization

Special Issue

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Message from the Editor-in-Chief

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